EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	963	measur\$5 near (surface adj roughness) same (wafer substrate)	US-PGPUB; USPAT	.OR ·	ON	2007/06/29 11:30
L4	4	measur\$5 near (surface adj roughness) same (wafer substrate) and "355"/\$.ccls.	US-PGPUB; USPAT	OR	OŃ	2007/06/29 11:30
S1	1	10/529893.app.	US-PGPUB; USPAT	OR	ON	2007/06/28 18:39
S2	8	("20040121245" "20050063445" " 20050064303" "20060003236" "2 0060003269" "6171730" "618748 2" "7050144").PN.	US-PGPUB; USPAT	OR	ON	2007/06/29 09:50
S3	46	deform near (mask pattern reticle) same pressure	US-PGPUB; USPAT	OR	ON	2007/06/29 09:55
S4	128	(deform stretch elongate) near (mask pattern reticle) and equation	US-PGPUB; USPAT	OR	ON	2007/06/29 09:58
S5	0	(deform) near (mask pattern reticle) and equation near pressure	US-PGPUB; USPAT	OR	ON	2007/06/29 09:58
S6	2	(deform) near (mask pattern reticle) and equation same pressure	US-PGPUB; USPAT	OR	ON	2007/06/29 09:58
S7	130	equation same (young\$2 and poisson\$2 and pressure and thickness)	US-PGPUB; USPAT	OR	ON	2007/06/29 10:05
S8	74	pressure.ab. and equation same (young\$2 and poisson\$2 and pressure and thickness)	US-PGPUB; USPAT	OR	ON	2007/06/29 10:05